




<b>Search Notes</b>  	Application/Control No.  10045397	Applicant(s)/Patent Under Reexamination  HASEGAWA, YUTAKA
	Examiner Tran, Philip B	Art Unit 2155

Notes	Date	Examiner
East and West and NPL	2/7/05	PBT
Updated Search	9/29/05	PBT
Updated Search	4/28/06	PBT
Updated Search	10/27/06	PBT
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	<p>Examiner</p> <p>Tran, Philip B</p>	<p>Art Unit</p> <p>2155</p>

Class	SubClass	Date	Examiner
709	206	2/7/05	PBT
709	217-219	2/7/05	PBT
709	231	2/7/05	PBT
709	203	2/7/05	PBT
Updated	Search	9/29/05	PBT
Updated	Search	4/28/06	PBT
Updated	Search	10/27/06	PBT

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<b>Interference Searched</b>  	Application/Control No.  10045397	Applicant(s)/Patent Under Reexamination  HASEGAWA, YUTAKA
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709	206	10/30/06	PBT
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